

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
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Examiner

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Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,552,192 B1	04-2003	Hanus et al.	544/280
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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